

## Details regarding VLAC-018 site

Accreditation No.	VLAC-018-1
Name of Laboratory	TUV SUD Ohtama, Ltd.
Test site name	Tokyo EMC Center
Address	2-8-20, Kurigi, Asao-ku, Kawasaki-shi, Kanagawa, Japan, 215-0033
Responsible person	Makoto Segawa
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### —SCOPE OF ACCREDITATION—

#### ***[Measurement Method]***

##### Emission Test

Radiated disturbance: Enclosure Port

Radiated field strength measurement (CISPR 16-2-3, ANSI C63.4:2003)

[Test Condition] On the ground reference plane, Measurement distance: 3m, 10m

Radiated magnetic field strength measurement (CISPR16-2-3)

Disturbance power measurement (CISPR16-2-2)

[Name of Test Facility] No.1 EMC test room, No.5 EMC test room

Conducted disturbance: AC mains port

Disturbance voltage measurement (CISPR 16-2-1, ANSI C63.4:2003)

[Test Condition] AMN (CISPR 16-1-2)

[Name of Test Facility] No.1 EMC test room(Anechoic Chamber, Shielded Room),  
No.3 EMC test room, No.5 EMC test room (Anechoic Chamber, Shielded Room)

Conducted disturbance: Telecommunications port

Disturbance voltage measurement (CISPR 22 Clause 9.6 and Annex C)

[Test Condition] AAN (CISPR 16-1-2)

Disturbance current measurement (CISPR 22 Clause 9.6 and Annex C)

[Test Condition] Current probe (CISPR 16-1-2)

[Name of Test Facility] No.1 EMC test room(Anechoic Chamber, Shielded Room),  
No.3 EMC test room, No.5 EMC test room (Anechoic Chamber, Shielded Room)

Conducted disturbance: DC mains port

Disturbance voltage measurement

[Test Condition] AMN, High Impedance Probe (CISPR 16-1-2)

[Name of Test Facility] No.1 EMC test room(Anechoic Chamber, Shielded Room),  
No.3 EMC test room, No.5 EMC test room (Anechoic Chamber, Shielded Room)

##### Immunity Test

ESD (IEC61000-4-2),

Radiated electromagnetic field strength (IEC61000-4-3),

EFT/B (IEC61000-4-4): AC mains port/Telecommunications port,

Surge (IEC61000-4-5): AC mains port/Telecommunications port,

RF conducted (IEC61000-4-6): AC mains port/Telecommunications port,

Power frequency magnetic field (IEC61000-4-8),

Interruptions and voltage variations/dip (IEC61000-4-11)

(Test Facilities) No.1 EMC test room (Anechoic Chamber),

No.5 EMC test room(Anechoic Chamber)

Except Radiated Immunity test for No.1 EMC test room (Anechoic Chamber, Shielded Room),

No.3 EMC test room, No.5 EMC test room (Anechoic Chamber, Shielded Room)

##### Harmonic Test in Public Low Voltage Systems

Harmonic current (IEC61000-3-2), Voltage fluctuations and flicker (IEC61000-3-3)

## ***[Measurement Standard]***

### **Emission Test**

V-3 : VCCI Technical Requirement  
FCC 47CFR/Part15 Subpart B/ANSI C63.4 (2003)  
FCC 47CFR/Part18 /MP-5  
CISPR11, CISPR14-1, CISPR22, EN55011, EN55014-1, EN55022  
J55001, J55014-1, J55022, CNS 13803, CNS 13438  
AS/NZS CISPR11, AS/NZS CISPR14-1, AS/NZS CISPR22  
IEC61000-6-3, IEC61000-6-4, EN61000-6-3, EN61000-6-4  
IEC60601-1-2(Particular requirement IEC60601-2 series),  
EN60601-1-2((Particular requirement EN60601-2 series)  
JIS T0601-1-2(Particular requirement JIS T0601-2 series)  
IEC61326-1(Particular requirement IEC61326-2 series),  
EN61326-1(Particular requirement EN61326-2 series), JIS C1806-1

### **Immunity Test**

IEC 61000-6-1, IEC 61000-6-2, EN 61000-6-1, EN 61000-6-2  
JIS C 61000-6-1, JIS C 61000-6-2  
IEC60601-1-2(Particular requirement IEC60601-2 series),  
EN60601-1-2((Particular requirement EN60601-2 series)  
JIS T0601-1-2(Particular requirement JIS T0601-2 series)  
IEC61326-1(Particular requirement IEC61326-2 series),  
EN61326-1(Particular requirement EN61326-2 series), JIS C1806-1

### **Harmonic Test in Public Low Voltage Systems**

IEC 61000-3-2, JIS C 61000-3-2, EN 61000-3-2, IEC 61000-3-3, EN 61000-3-3  
IEC 61000-6-3, IEC 61000-6-4, EN 61000-6-3, EN 61000-6-4  
IEC60601-1-2(Particular requirement IEC60601-2 series),  
EN60601-1-2((Particular requirement EN60601-2 series)  
JIS T0601-1-2(Particular requirement JIS T0601-2 series)  
IEC61326-1(Particular requirement IEC61326-2 series),  
EN61326-1(Particular requirement EN61326-2 series), JIS C1806-1